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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10006398	FILING DATE 11/30/2001	CLASS 356	SUBCLASS 401	GAU 2877	EXAMINER Lauchman
**APPLICANTS: Yates Colin; Pasch Nicholas; Eib Nicholas;					
**CONTINUING DATA VERIFIED: none <i>gl</i> 9/25/03					
** FOREIGN APPLICATIONS VERIFIED: none <i>gl</i> 9/25/03					
PG-PUB <input checked="" type="checkbox"/> DO NOT PUBLISH		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		ATTORNEY DOCKET NO			
35 USC 119 conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no		01-234			
Verified and Acknowledged Examiners's initials <i>gl</i>					
TITLE : Alignment process for integrated circuit structures on semiconductor substrate using scatterometry measurements of latent images in spaced apart test fields on substrate					
U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)					

NOTICE OF ALLOWANCE MAILED		Assistant Examiner		CLAIMS ALLOWED	
				Total Claims	Print Claim for O.G.
ISSUE FEE		Primary Examiner		DRAWING	
Amount Due	Date Paid			Sheets Drawg.	Figs. Drawg.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE		Application Examiner	
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